

ADAPTIVE INTEGRATED CIRCUIT BASED ON TRANSISTOR CURRENT MEASUREMENTS

Abstract

BUR920020148US13 A method of tuning an integrated circuit on an integrated circuit chip including: performing a drain current at saturation measurement of one or more test field effect transistors on the integrated circuit chip; selectively programming fuses of a bank of fuses on the integrated circuit chip based on the drain current at saturation measurement; and tuning an output of the integrated circuit based on a pattern of blown and un-blown fuses in the bank of fuses.